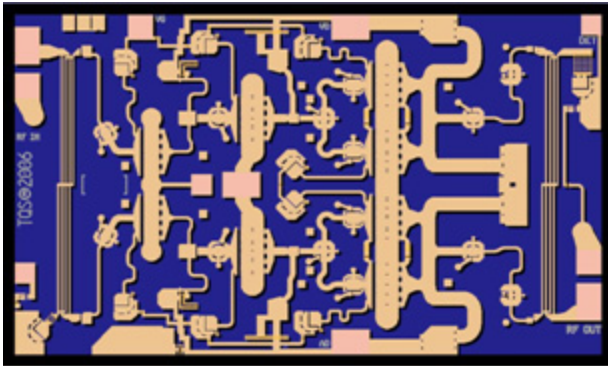


# K Band High Linearity Power Amplifier

# TGA4530

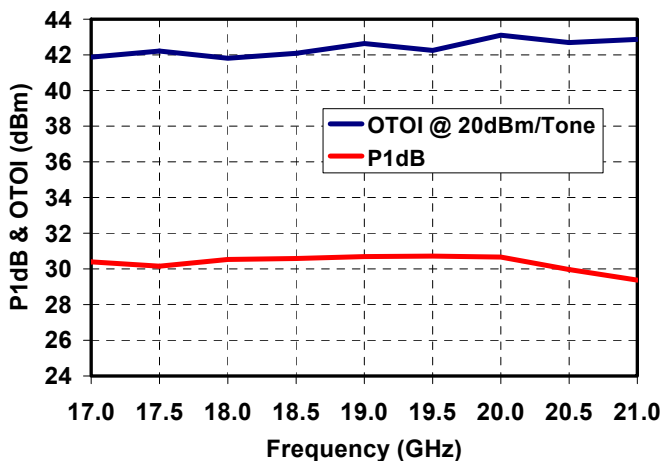
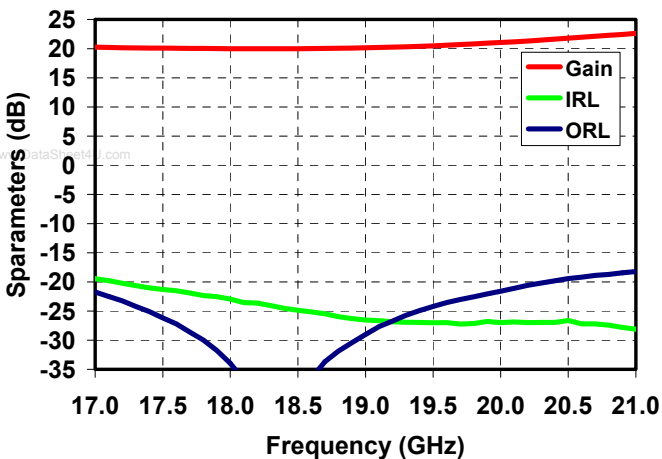


## Key Features

- Frequency Range: 17 - 21 GHz
- 20 dB Gain
- 30 dBm nominal P1dB
- 42dBm nominal OTOI
- 20 dB Return Loss
- Bias 5 - 7 V @ 825 mA
- 0.25 um 3MI pHEMT technology
- Chip Dimensions 2.43 x 1.45 x .1mm

## Measured Fixtured Data

Bias Conditions:  $V_d = 7V$ ,  $I_d = 825mA$



## Primary Applications

- Point-to-Point Radio
- K Band Sat-Com

## Product Description

The TriQuint TGA4530 is a High Power Amplifier MMIC for 17 – 21GHz applications. The part is designed using TriQuint’s 0.25um 3MI pHEMT production process.

The TGA4530 nominally provides 30dBm output power @ 1dB gain compression and 42dBm OTOI at a bias of 7V and 825mA. The typical gain is 20dB.

The part is ideally suited for low cost emerging markets such as Point-to-Point Radio, and K-band Satellite Communications.

The TGA4530 is 100% DC and RF tested on-wafer to ensure performance compliance.

The TGA4530 has a protective surface passivation layer providing environmental robustness.

Lead-Free & RoHS compliant

Note: Device is early in the characterization process prior to finalizing all electrical specifications. Specifications are subject to change without notice

**TABLE I**  
**MAXIMUM RATINGS 1/**

<b>SYMBOL</b>	<b>PARAMETER</b>	<b>VALUE</b>	<b>NOTES</b>
V <sub>d</sub>	Positive Supply Voltage	8 V	<u>2/</u>
V <sub>g</sub>	Negative Supply Voltage Range	-5V TO 0V	
I <sub>d</sub>	Positive Supply Current	1.75 A	<u>2/</u>
I <sub>G</sub>	Gate Supply Current	35 mA	
P <sub>IN</sub>	Input Continuous Wave Power	26 dBm	<u>2/</u>
P <sub>D</sub>	Power Dissipation	5.8 W	<u>2/</u> , <u>3/</u>
T <sub>CH</sub>	Operating Channel Temperature	150 °C	<u>3/</u> , <u>4/</u>
T <sub>M</sub>	Mounting Temperature (30 Seconds)	320 °C	
T <sub>STG</sub>	Storage Temperature	-65 to 150 °C	

- 1/ These ratings represent the maximum operable values for this device.
- 2/ Combinations of supply voltage, supply current, input power, and output power shall not exceed P<sub>D</sub>.
- 3/ When operated at this power dissipation with a base plate temperature of 65<sup>0</sup>C, the median life is 1.0E+6 hrs.
- 4/ Junction operating temperature will directly affect the device median time to failure (MTTF). For maximum life, it is recommended that junction temperatures be maintained at the lowest possible levels.

**TABLE II**  
**ELECTRICAL CHARACTERISTICS**  
(Ta = 25 °C Nominal)

PARAMETER	TYPICAL	UNITS
Frequency Range	17 - 21	GHz
Drain Voltage, Vd	7	V
Drain Current, Id	825	mA
Gate Voltage, Vg	-0.45	V
Small Signal Gain, S21	20	dB
Input Return Loss, S11	20	dB
Output Return Loss, S22	20	dB
Saturated Output Power @ Pin = 16dBm, Psat	32	dBm
Output Power @ 1dB Gain Compression, P1dB	30	dBm
Output Third Order Intercept, OTOI @ 20dBm/Tone	42	dBm
Small Signal Gain Temperature Coefficient	-0.03	dB/°C
Noise Figure @ 19GHz	6	dB

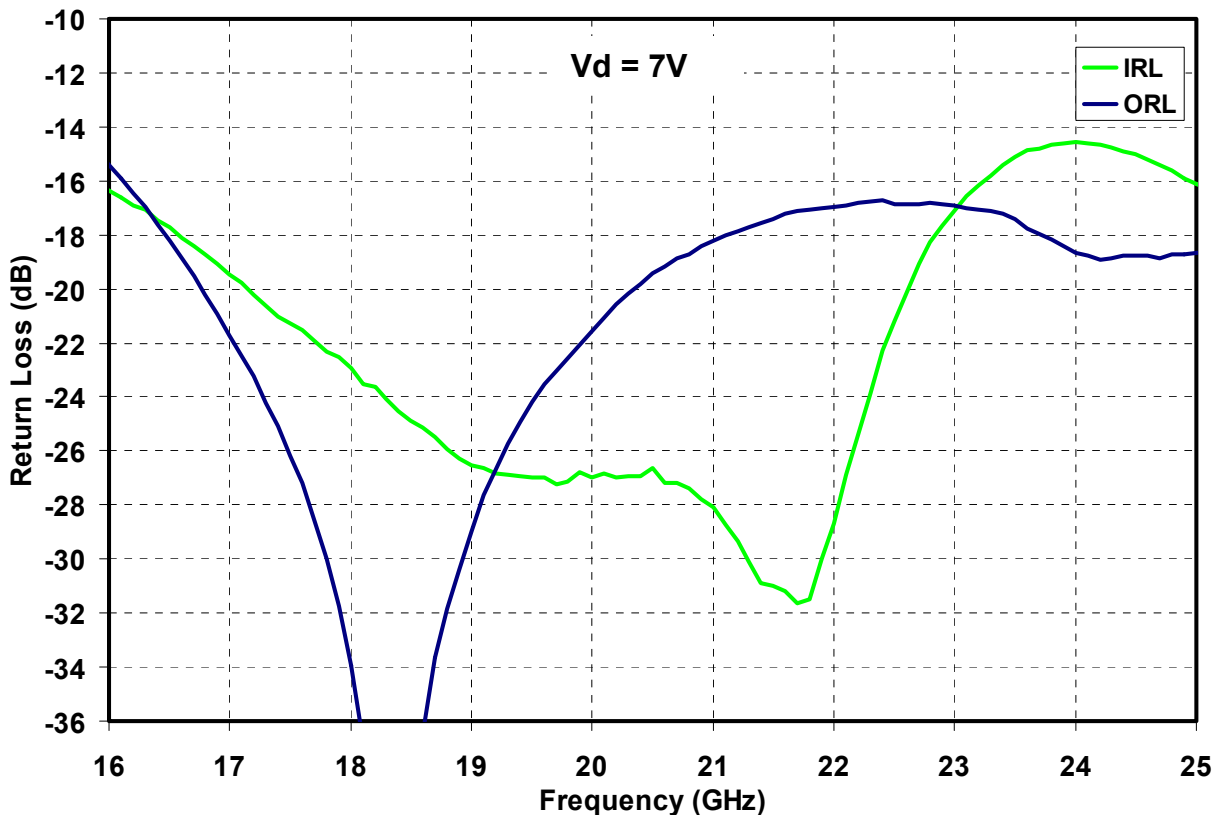
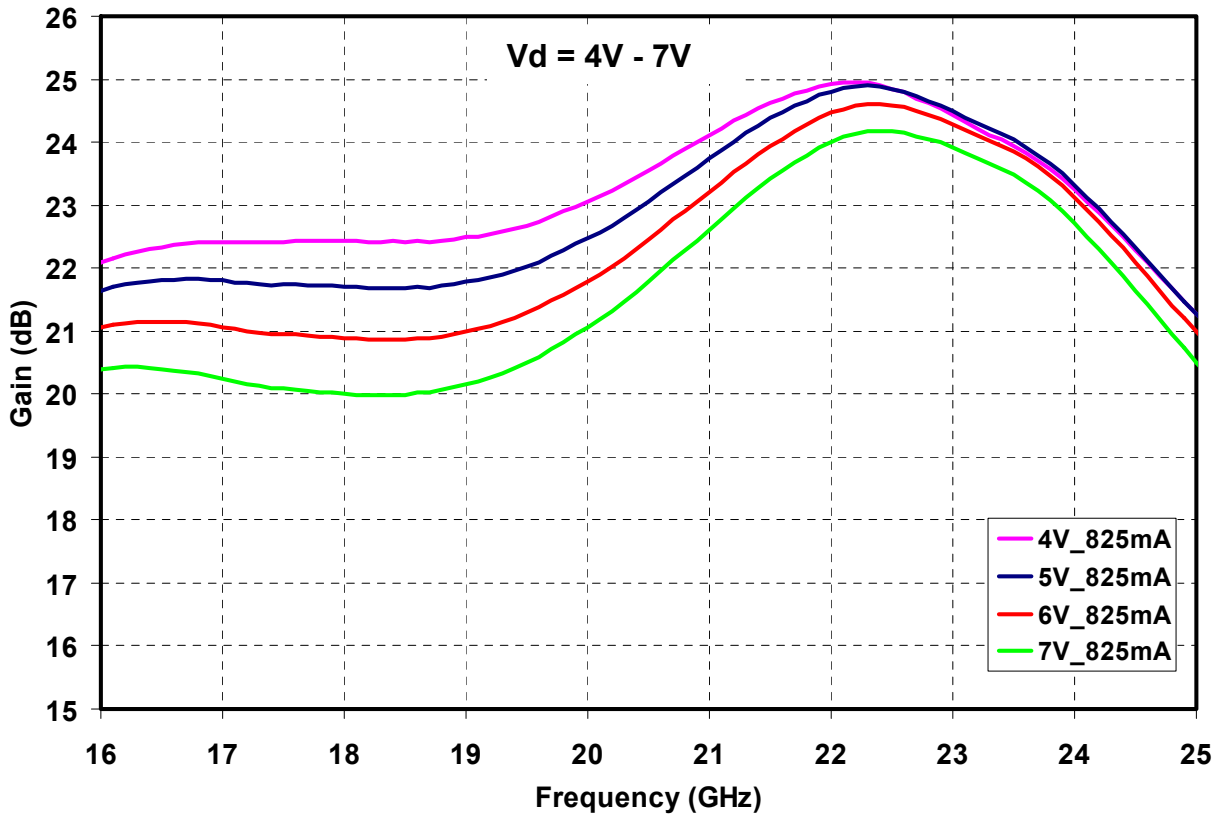
**TABLE III**  
**THERMAL INFORMATION**

PARAMETER	TEST CONDITIONS	T <sub>CH</sub> (°C)	θ <sub>JC</sub> (°C/W)	T <sub>M</sub> (HRS)
θ <sub>JC</sub> Thermal Resistance (channel to Case)	Vd = 7 V Id = 825 mA P <sub>diss</sub> = 5.78 W Small Signal	150	14.7	1.0E+6
θ <sub>JC</sub> Thermal Resistance (channel to Case)	Vd = 7 V Id = 1050 mA @ Psat P <sub>out</sub> = 1.6 W (RF) P <sub>diss</sub> = 5.75 W	150	14.7	1.0E+6

Note: Assumes eutectic attach using 1.5 mil 80/20 AuSn mounted to a 20 mil CuMo Carrier at 65°C baseplate temperature.

**Measured Data**  
Bias Conditions:  $I_{dq} = 825 \text{ mA}$

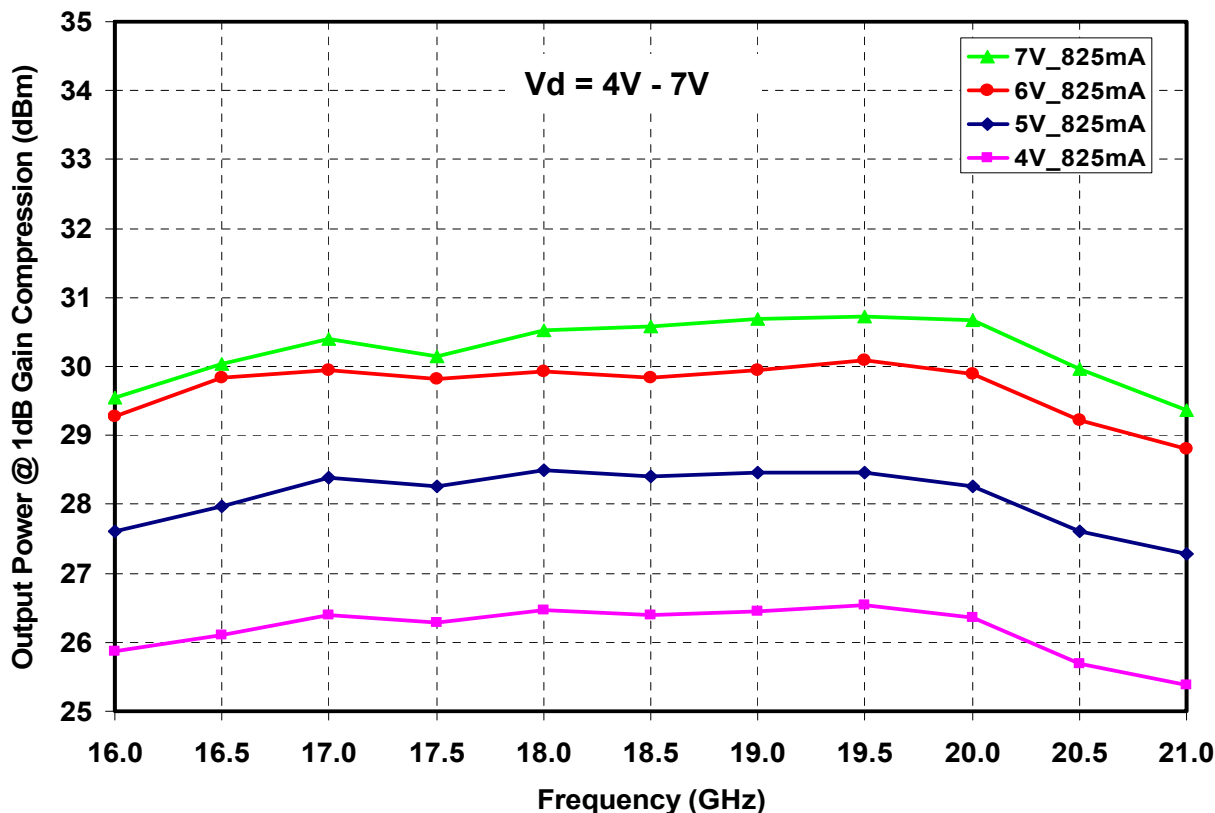
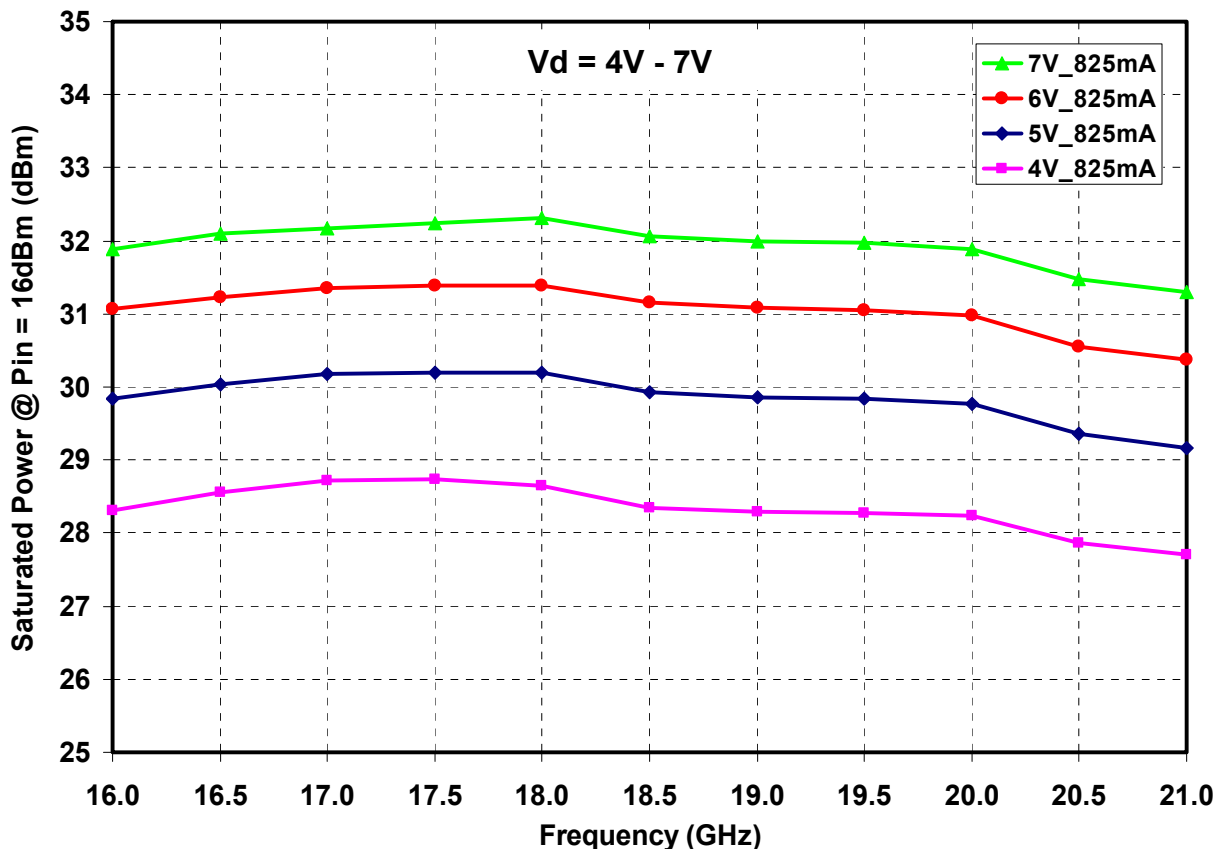
**TGA4530**



**Measured Data**

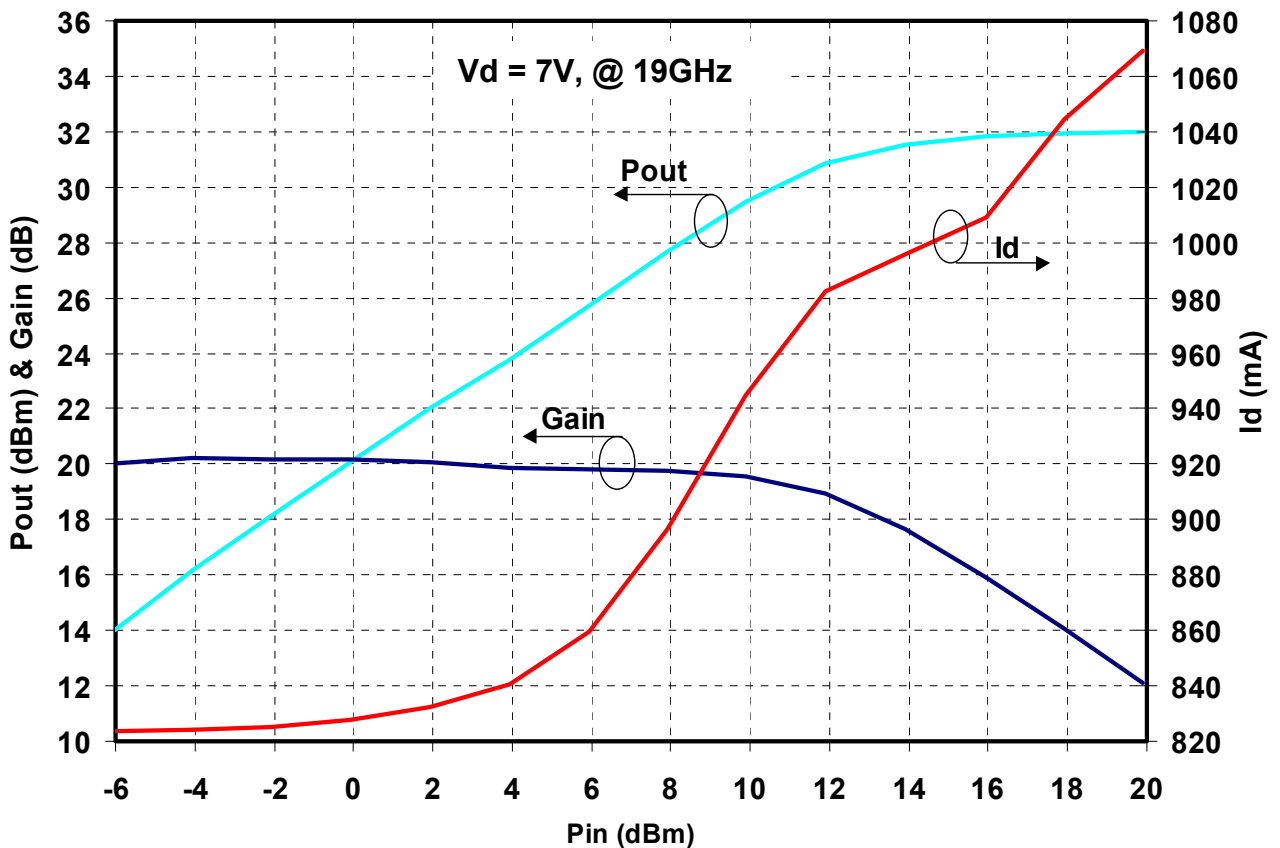
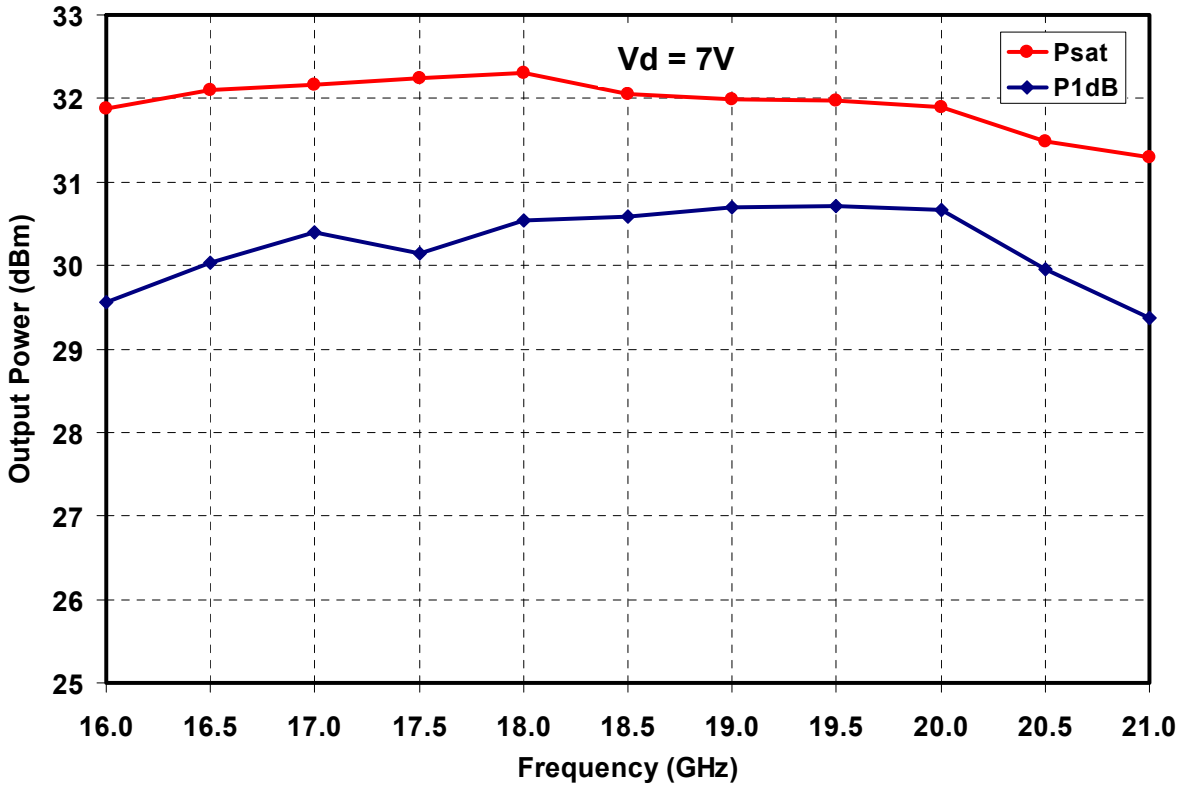
**TGA4530**

Bias Conditions:  $V_d = 4V - 7V$ ,  $I_{dq} = 825\text{ mA}$



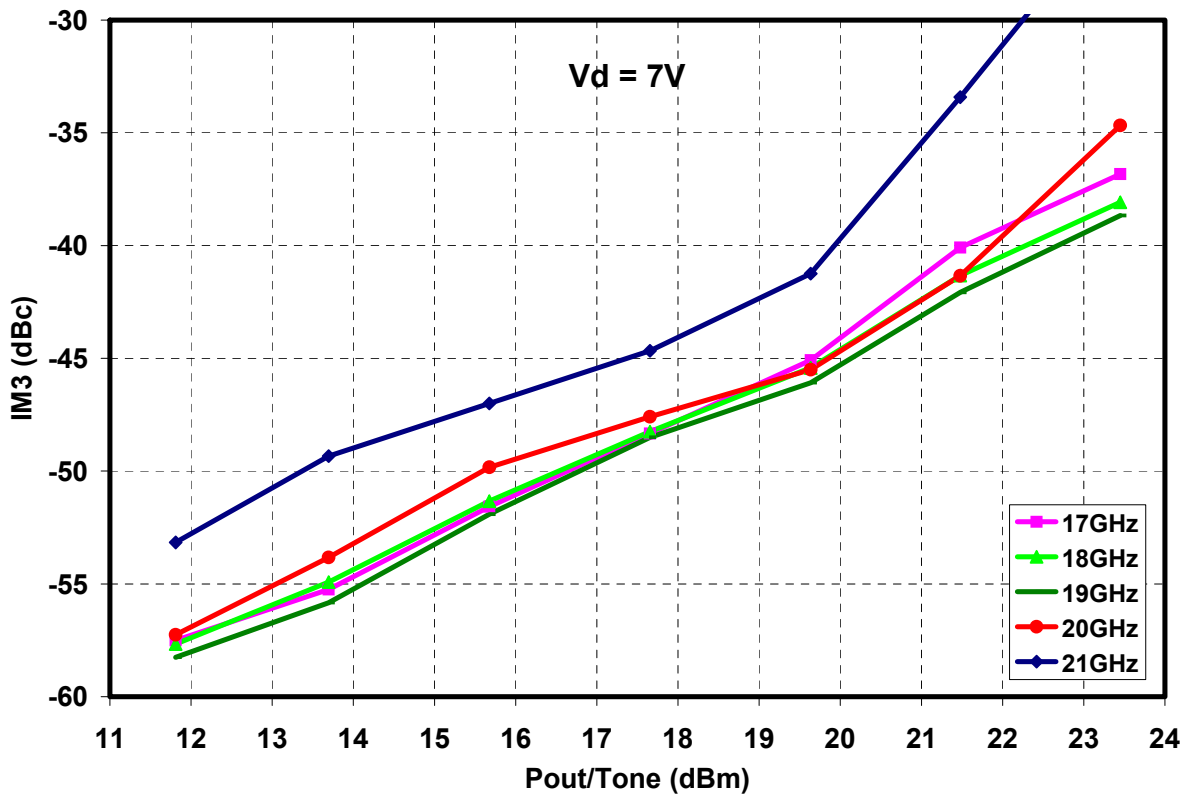
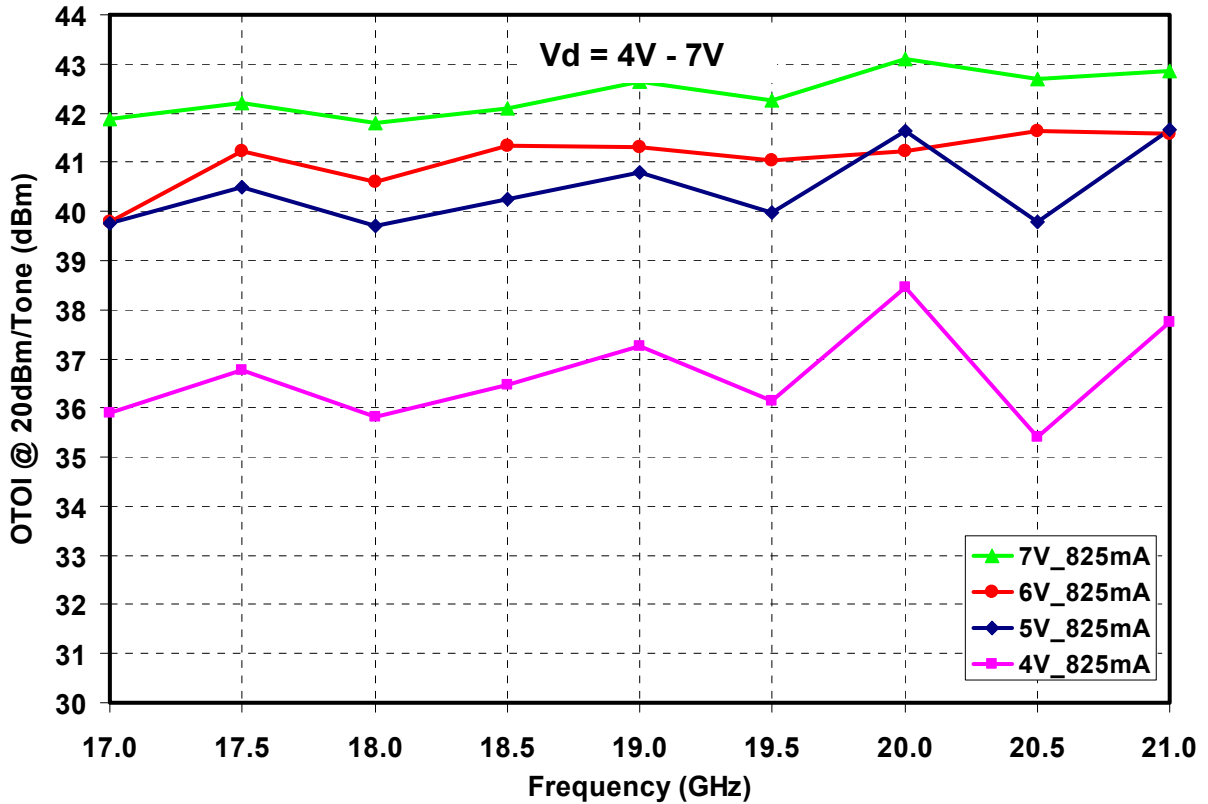
**Measured Data**

Bias Conditions:  $V_d = 7V$ ,  $I_{dq} = 825\text{ mA}$



**Measured Data**

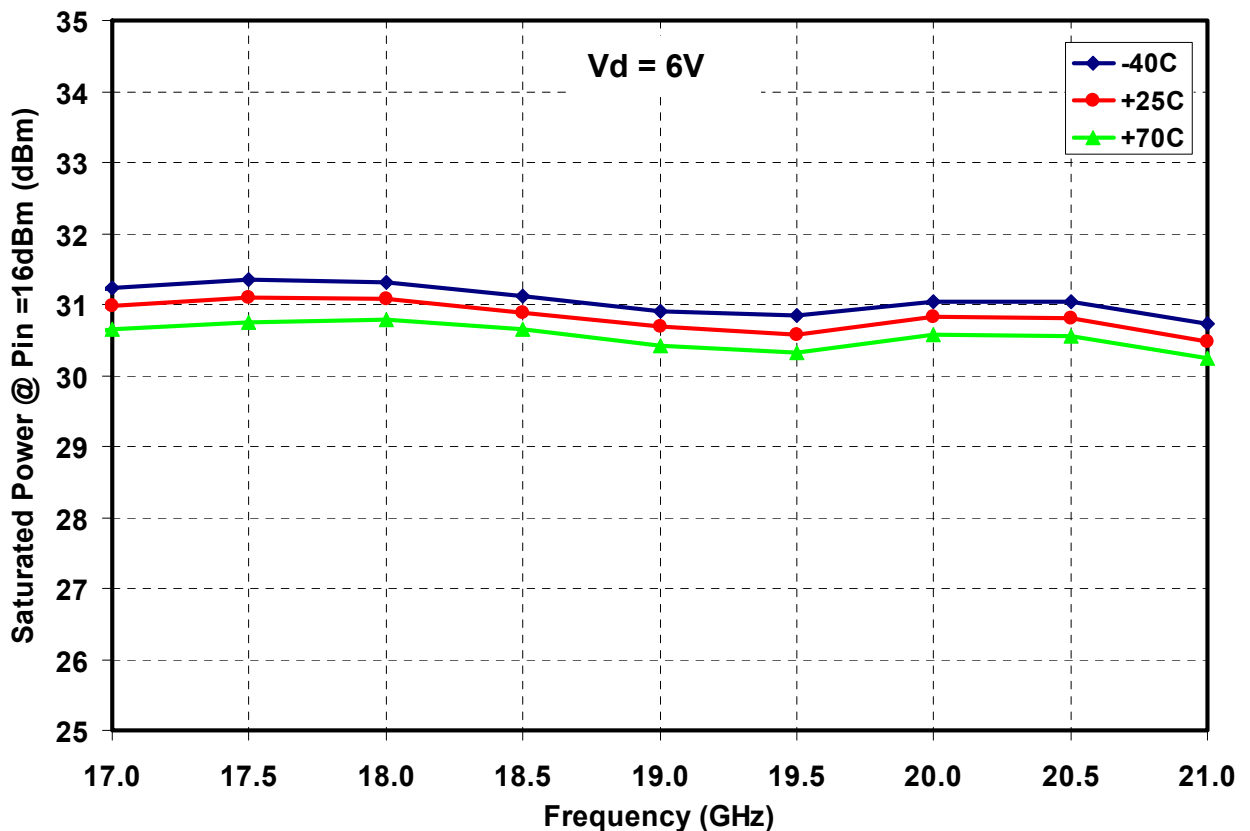
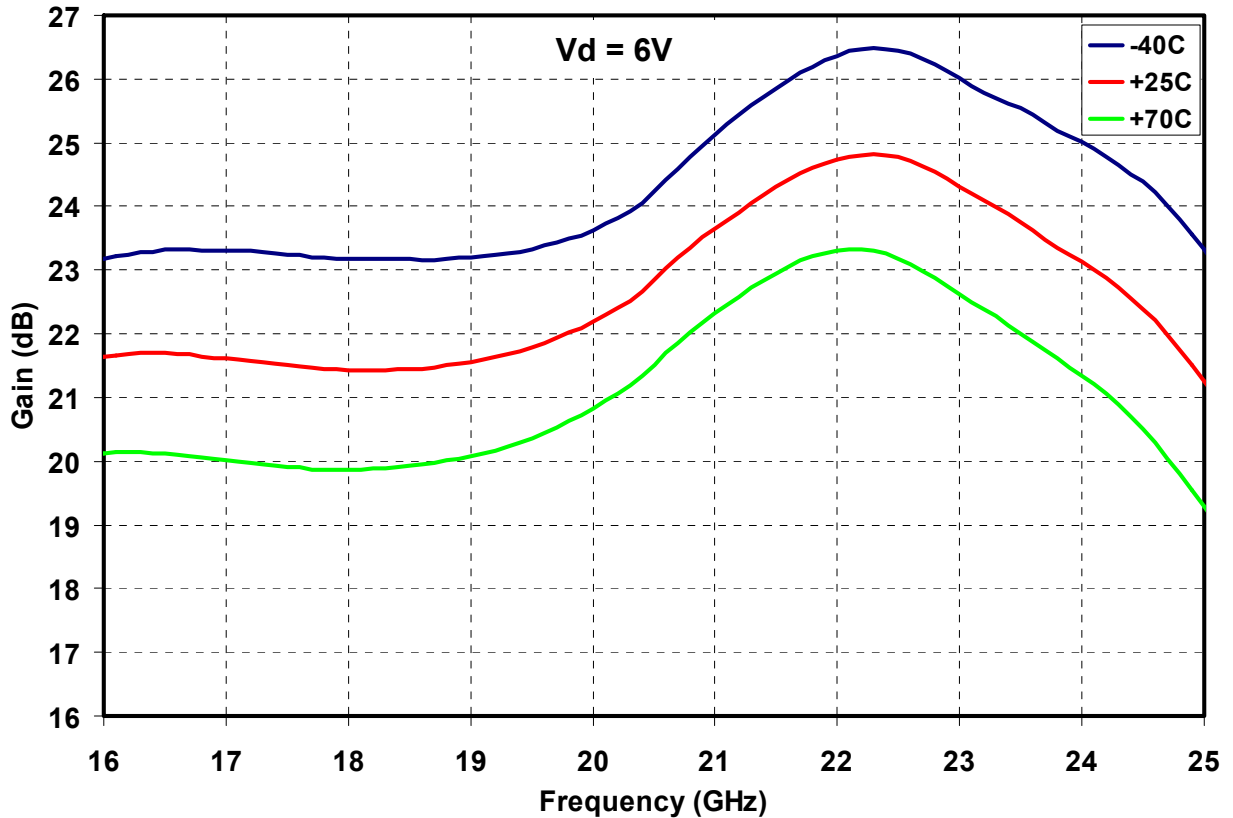
Bias Conditions:  $V_d=4V - 7V$ ,  $I_{dq} = 825 \text{ mA}$ ,  $\Delta f = 1\text{MHz}$



**Measured Data**

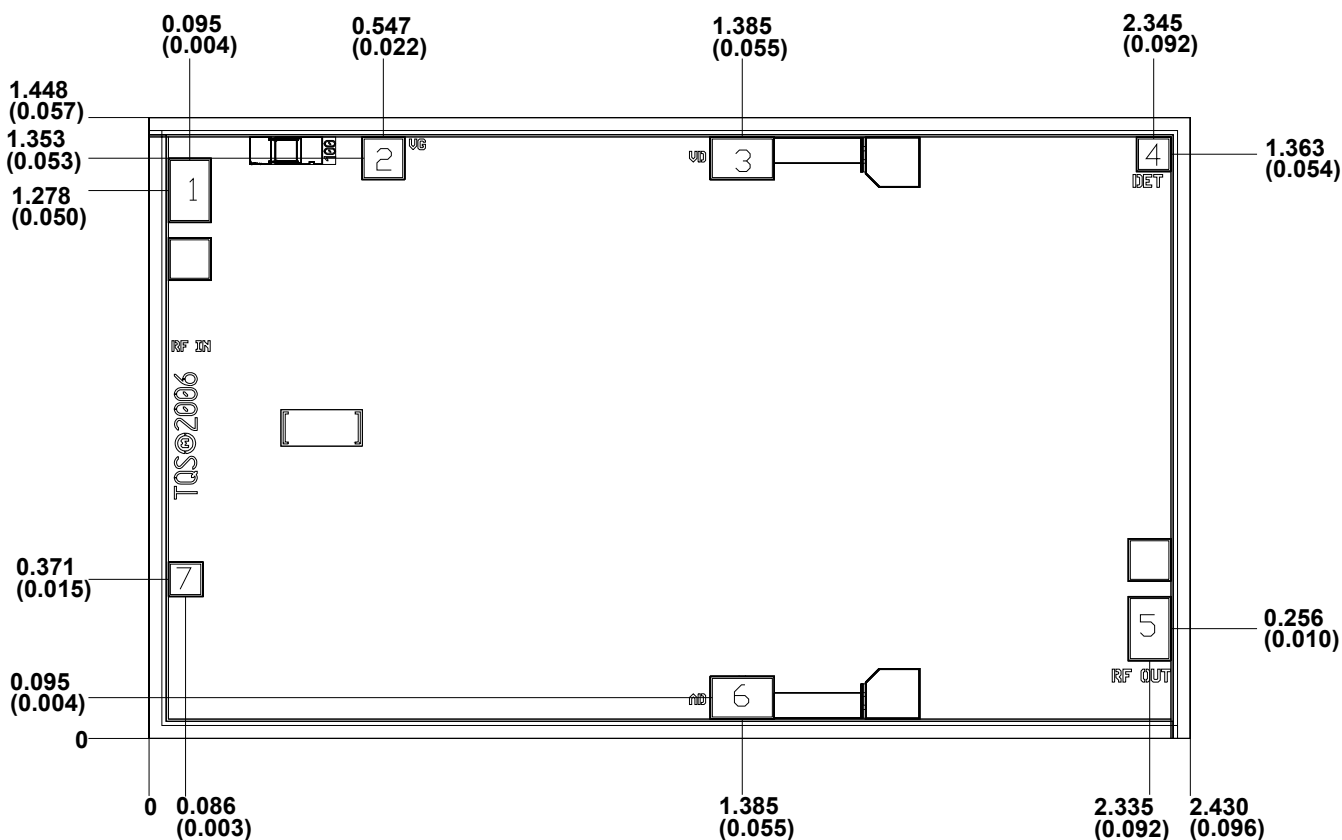
**TGA4530**

Bias Conditions:  $V_d = 6V$ ,  $I_{dq} = 825\text{ mA}$





## Mechanical Drawing



Units: Millimeters (inches)

Thickness: 0.10 (0.004)

Chip edge to bond pad dimensions are shown to center of bond pad

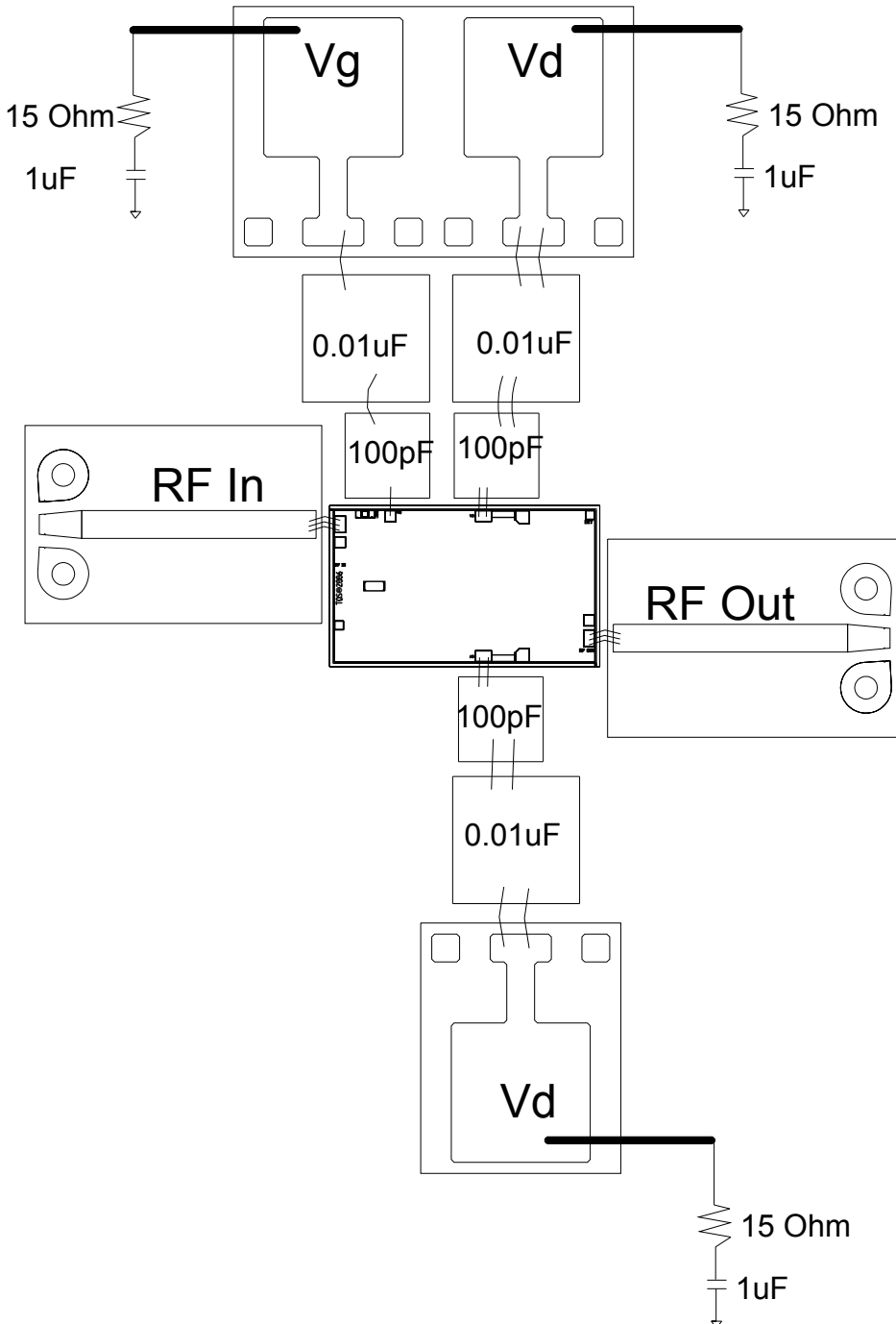
Chip size tolerance: +/- 0.05 (0.002)

**GND IS BACKSIDE OF MMIC**

Bond pad # 1	(RF Input)	0.100 x 0.150 (0.004 x 0.006)
Bond pad # 2	(Vg)	0.100 x 0.100 (0.004 x 0.004)
Bond pad # 3	(Vd)	0.150 x 0.100 (0.006 x 0.004)
Bond pad # 4	(Vdet)	0.081 x 0.081 (0.003 x 0.003)
Bond pad # 5	(RF Out)	0.100 x 0.150 (0.004 x 0.006)
Bond pad # 6	(Vd)	0.150 x 0.100 (0.006 x 0.004)
Bond pad # 7	(Vref)	0.081 x 0.081 (0.003 x 0.003)

*GaAs MMIC devices are susceptible to damage from Electrostatic Discharge. Proper precautions should be observed during handling, assembly and test.*

**Recommended Assembly Diagram**



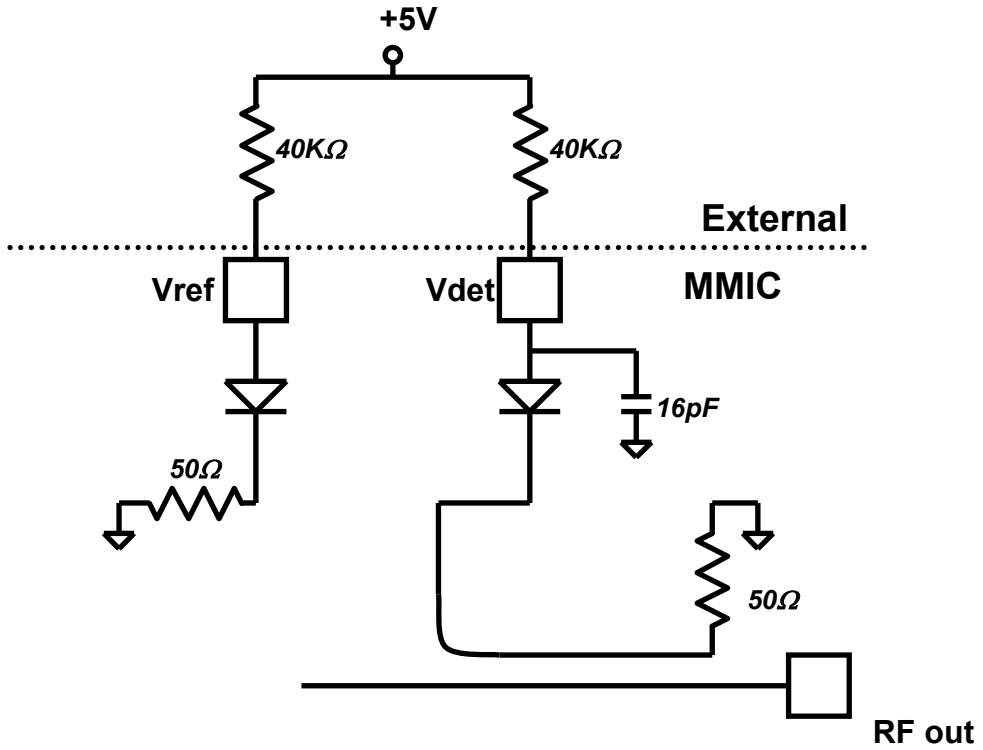
**Vd = 5 to 7V**

**Id = 825mA**

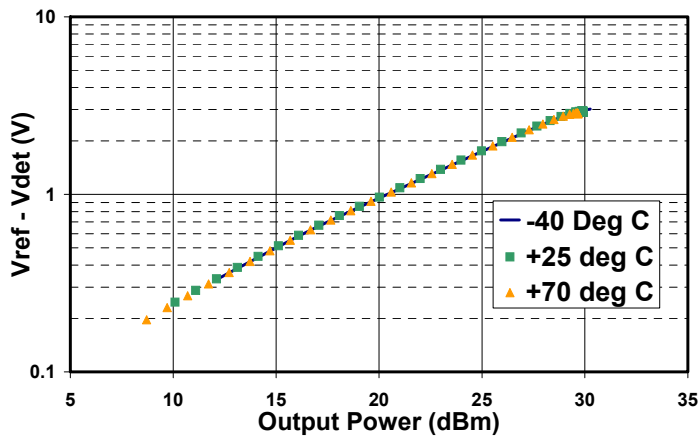
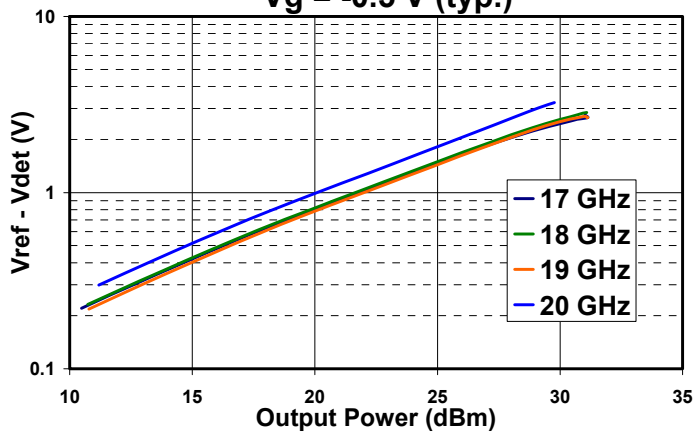
**Vg = -0.45V (Typical for 7V Vd bias)**

*GaAs MMIC devices are susceptible to damage from Electrostatic Discharge. Proper precautions should be observed during handling, assembly and test.*

**Power Detector**



**Vd = 6V, Id = 825mA**  
**Vg = -0.5 V (typ.)**



## Assembly Process Notes

Reflow process assembly notes:

- Use AuSn (80/20) solder with limited exposure to temperatures at or above 300<sup>0</sup>C (30 seconds max).
- An alloy station or conveyor furnace with reducing atmosphere should be used.
- No fluxes should be utilized.
- Coefficient of thermal expansion matching is critical for long-term reliability.
- Devices must be stored in a dry nitrogen atmosphere.

Component placement and adhesive attachment assembly notes:

- Vacuum pencils and/or vacuum collets are the preferred method of pick up.
- Air bridges must be avoided during placement.
- The force impact is critical during auto placement.
- Organic attachment can be used in low-power applications.
- Curing should be done in a convection oven; proper exhaust is a safety concern.
- Microwave or radiant curing should not be used because of differential heating.
- Coefficient of thermal expansion matching is critical.

Interconnect process assembly notes:

- Thermosonic ball bonding is the preferred interconnect technique.
- Force, time, and ultrasonics are critical parameters.
- Aluminum wire should not be used.
- Maximum stage temperature is 200<sup>0</sup>C.

## Ordering Information

Part	Package Style
TGA4530	Chip

***GaAs MMIC devices are susceptible to damage from Electrostatic Discharge. Proper precautions should be observed during handling, assembly and test.***